METHOD FOR INSERTION OF TEST POINTS INTO INTEGRATED
LOGIC CIRCUIT DESIGNS

ABSTRACT

A method of inserting test points in a circuit design includes selecting a node in the circuit design, determining a driver cell of the node, selecting a replacement cell for the driver cell and replacing the driver cell in the circuit design with the replacement cell. The replacement cell has the same function of the driver cell as well as a test point function. Additionally, the replacement cell is chosen so as not to break timing.

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